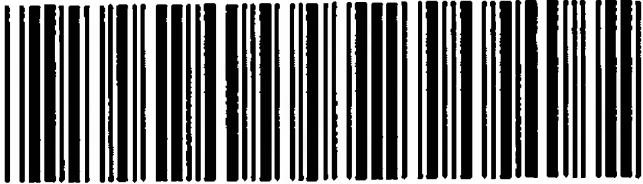


Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/617,826	CHEN ET AL.	
	Examiner	Art Unit	
	Leon J. Harper	2166	

SEARCHED			
Class	Subclass	Date	Examiner
707	104.1, 10	11/17/2006	LJH

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
707	10	11/17/2006	LJH
707	104.1	11/17/2006	LJH

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR